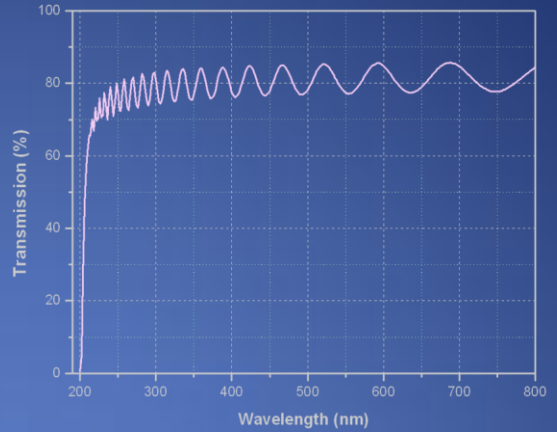
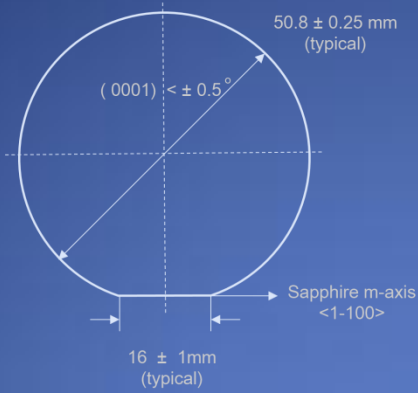


AlN Template on sapphire

Side View



Top View



◆ Typical specifications of AlN template

◆ Optical transmission spectra (@ 0.5 μm thick AlN)

Properties		Typical Specifications
Substrate	Material	Sapphire
	Diameter	50.8 mm ± 0.25mm
	Thickness	430 μm ± 25 μm
	Orientation	C-plane (0001) ± 0.2°
	Backside finish	Polished
AlN layer	Thickness	1.6 ~ 1.8 μm
	FWHM of X-ray Rocking Curve (ω-scan)	< 600 arcsec for (102)
	Transmission @ 260 nm (Baseline : Sapphire)	> 70%
	Surface of AlN	Ra < 0.5nm
	Edge Excursion Zone	< 3 mm
	Marco Defects (> 50 μm)	< 5ea/cm ²
	Conductivity	Insulating